

Notice of References Cited	Application/Control No. 10/802,544	Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner Paul D. Kim	Art Unit 3729	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,036,813	03-2000	Schulz et al.	156/307.7
*	B	US-6,034,843	03-2000	Tsujino et al.	360/265.8
*	C	US-6,005,747	12-1999	Gilovich, Paul A.	360/98.07
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	K	US-			
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NON-PATENT DOCUMENTS

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	U	"ESD damage of GMR sensors at head stack assembly"; Zeng, R.; Yu Qun; Fenggang Zhao; Hong Tian; Electrical Overstress/Electrostatic Discharge Symposium Proceedings, 1999□□28-30 Sept. 1999; Page(s):380 - 384.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.